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Bhowmick, S.S.; Madria, S.K.; Wee Keong Ng;

Knowledge and Data Engineering, IEEE Transactions on , Volume: 15 , Issue: 2, March-April 2003

Pages: 423 - 441

[Abstract] [PDF Full-Text (2779 KB)] **IEEE JNL**

2 Updating distributed materialized views

Segev, A.; Park, J.;

Knowledge and Data Engineering, IEEE Transactions on , Volume: 1 , Issue:

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Pages:173 - 184

[Abstract] [PDF Full-Text (1128 KB)]

3 Practical lineage tracing in data warehouses

Cui, Y.; Widom, J.;

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[Abstract] [PDF Full-Text (192 KB)] **IEEE CNF**

4 Concurrent maintenance of views using multiple versions

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de Amo, S.; Alves, M.H.F.;

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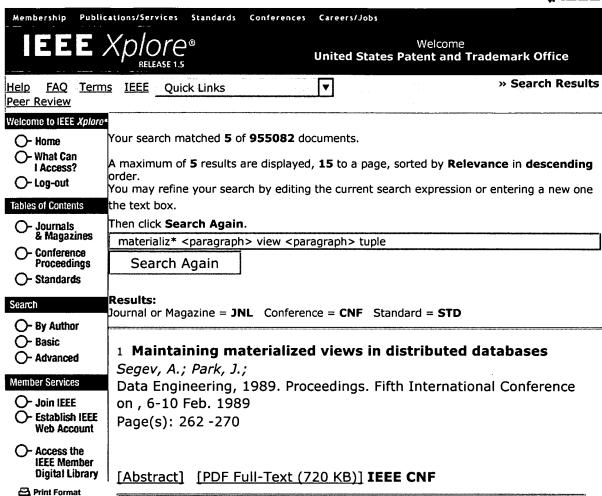
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